


<b>Search Notes</b> 	<b>Application/Control No.</b> 10566435	<b>Applicant(s)/Patent Under Reexamination</b> SHIROKURA ET AL.
	<b>Examiner</b> Meless N Zewdu	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
455	7, 11.1, 13.1, 15-18, 20-22, 62, 66.1, 101-103, 403, 422.1, 424-425, 426.1-426.2, 445-446, 524-526, 550.1, 554.1-554.2, 555, 556.1-556.2, 560-561	3/31/08	M.Z.
370	218, 226, 279, 293, 315-316, 328, 338, 352-357, 395.52-395.53, 473, 492, 501, 901, 908-913	3/31/08	M.Z.
375	211-212, 214, 267, 299, 346-352	3/31/08	M.Z.

SEARCH NOTES		
Search Notes	Date	Examiner
Searched: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM TDB	3/31/08	M.Z.
Searched: by inventors and assignee; by text and class-subclass	3/31/08	M.Z.
Search has been updated.	10/19/08	M.Z.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Meless N Zewdu/ Primary Examiner.Art Unit 2617
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